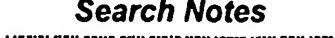


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/642,790	MURAKAMI, TAKEHIKO
	Examiner	Art Unit
	Randall Chin	1744

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
SAME AS ABOVE		11/09/65	RC